

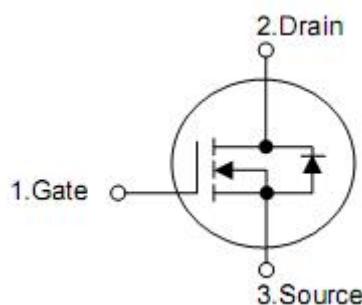
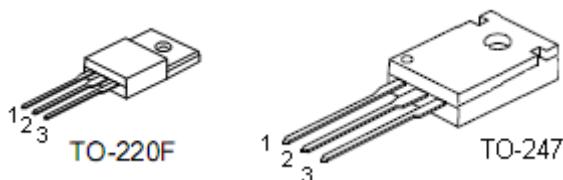
## 1. Description

The KIA18N50H N-Channel enhancement mode silicon gate power MOSFET is designed for high voltage, high speed power switching applications such as high efficiency switched mode power supplies, active power factor correction.

## 2. Features

- $R_{DS(on)}=0.25\Omega$  @  $V_{GS}=10V$
- Low gate charge ( typical 50nC)
- Fast switching capability
- Avalanche energy specified
- Improved dv/dt capability

## 3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source

## 4. Absolute maximum ratings

(T <sub>c</sub> = 25 °C , unless otherwise notes)					
Parameter	Symbol	Ratings		Units	
		TO220F	TO247		
Drain-source voltage	V <sub>DSS</sub>	500		V	
Gate-source voltage	V <sub>GSS</sub>	+30		V	
Drain current continuous	I <sub>D</sub>	18.0*	18.0	A	
		10.8*	10.8	A	
Drain current pulsed (note1)	I <sub>DP</sub>	72*	72	A	
Avalanche energy	E <sub>AR</sub>	23.5	23.5	mJ	
	E <sub>AS</sub>	990	990	mJ	
Peak diode recovery dv/dt (note 3)	dv/dt	4.5		V/ns	
Total power dissipation	P <sub>D</sub>	38.5	235	W	
		0.3	1.88	W/°C	
Junction temperature	T <sub>J</sub>	+150		°C	
Storage temperature	T <sub>STG</sub>	-55~+150		°C	

\*Drain current limited by maximum junction temperature.

## 5. Thermal characteristics

Parameter	Symbol	Ratings		Units
		TO220F	TO247	
Thermal resistance,junction-ambient	R <sub>thJA</sub>	62.5	40	°C/W
Thermal resistance,case-to-sink typ.	R <sub>thCS</sub>	-	-	
Thermal resistance,Junction-case	R <sub>thJC</sub>	3.3	0.52	

## 6. Electrical characteristics

( $T_J=25^\circ\text{C}$ ,unless otherwise notes)

Parameter	Symbol	Conditions	Min	Typ	Max	Units	
<b>Off characteristics</b>							
Drain-source breakdown voltage	$\text{BV}_{\text{DSS}}$	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	500	-	-	V	
Zero gate voltage drain current	$I_{\text{DSS}}$	$V_{\text{DS}}=500\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	$\mu\text{A}$	
		$V_{\text{DS}}=400\text{V}, T_{\text{C}}=125^\circ\text{C}$	-	-	10	$\mu\text{A}$	
		$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA	
Gate-body leakage current	$I_{\text{GSS}}$	$V_{\text{GS}}=-30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	-100	nA	
		$V_{\text{GS}}=30\text{V}, V_{\text{DS}}=0\text{V}$	-	-	100	nA	
Breakdown voltage temperature coefficient	$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$I_{\text{D}}=250\mu\text{A}$	TO220F TO247	-	0.6 0.5	-	V/ $^\circ\text{C}$
<b>On characteristics</b>							
Gate threshold voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	3.0	-	5.0	V	
Static drain-source on-resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=9\text{A}$	-	0.25	0.32	$\Omega$	
<b>Dynamic characteristics</b>							
Input capacitance	$C_{\text{iss}}$	$V_{\text{DS}}=25\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	-	2500	-	pF	
Output capacitance	$C_{\text{oss}}$		-	400	-	pF	
Reverse transfer capacitance	$C_{\text{rss}}$		-	40	-	pF	
<b>Switching characteristics</b>							
Turn-on delay time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}}=250\text{V}, I_{\text{D}}=18.0\text{A}, R_{\text{G}}=25\Omega$ (note4,5)	-	70	-	ns	
Rise time	$t_r$		-	190	-	ns	
Turn-off delay time	$t_{\text{d}(\text{off})}$		-	100	-	ns	
Fall time	$t_f$		-	100	-	ns	
Total gate charge	$Q_g$	$V_{\text{DS}}=400\text{V}, I_{\text{D}}=18.0\text{A}, V_{\text{GS}}=10\text{V}$ (note4,5)	-	50	-	nC	
Gate-source charge	$Q_{\text{gs}}$		-	14	-	nC	
Gate-drain charge	$Q_{\text{gd}}$		-	22	-	nC	
<b>Drain-source diode characteristics</b>							
Drain-source diode forward voltage	$V_{\text{SD}}$	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=18.0\text{A}$	TO220F TO247	-	-	1.5 1.4	V
Continuous drain-source current	$I_{\text{SD}}$			-	-	18.0	A
Pulsed drain-source current	$I_{\text{SM}}$			-	-	72	A
Reverse recovery time	$t_{\text{rr}}$	$I_{\text{SD}}=18.0\text{A}$ $dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$ (note4)	-	550	-	ns	
Reverse recovery charge	$Q_{\text{rr}}$		-	5.5	-	$\mu\text{C}$	

Note:1 Repetitive rating: pulse width limited by maximum junction temperature

2.  $L=5.5\text{mH}, I_{\text{AS}}=18.0\text{A}, V_{\text{DD}}=50\text{V}, R_{\text{G}}=25\Omega$ ,staring  $T_J=25^\circ\text{C}$

3.  $I_{\text{SD}}\leq 18.0\text{A}, dI/dt\leq 200\text{A}/\mu\text{s}, V_{\text{DD}}\leq \text{BV}_{\text{DSS}}$ , staring  $T_J=25^\circ\text{C}$

4. Pulse test: pulse width  $\leq 300\mu\text{s}$ ,duty cycle  $\leq 2\%$

5. Essentially independent of operating temperature

## 7. Test circuits and waveforms

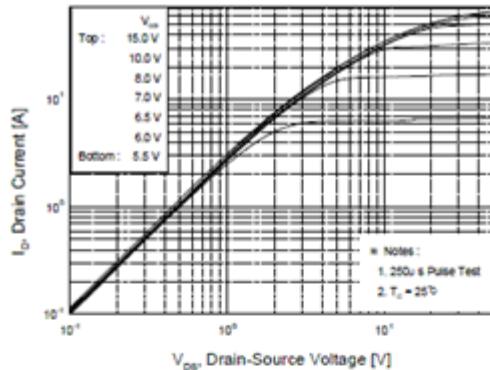


Figure 1. On-Region Characteristics

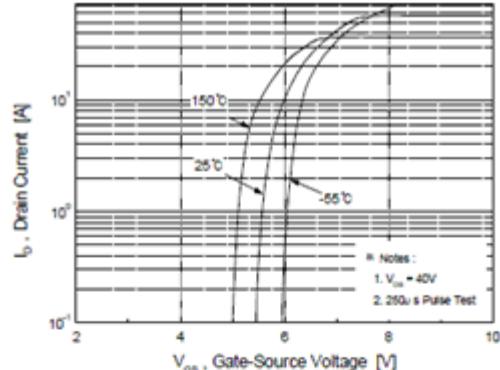


Figure 2. Transfer Characteristics

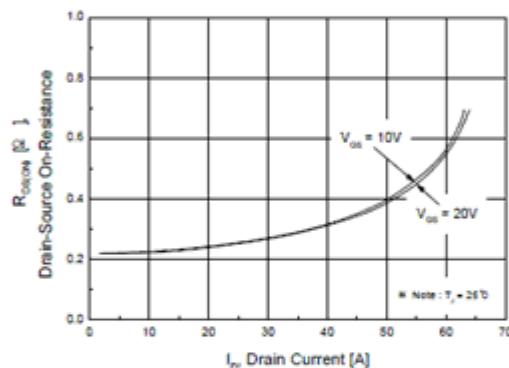


Figure 3. On-Resistance Variation vs  
Drain Current and Gate Voltage

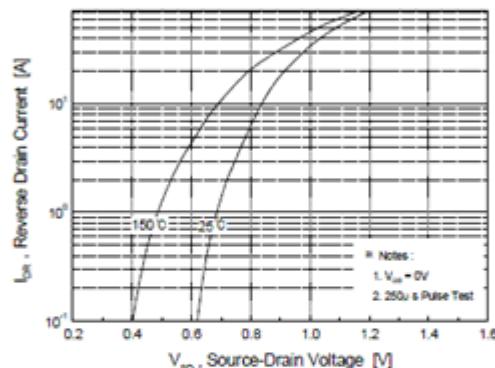


Figure 4. Body Diode Forward Voltage Variation  
with Source Current and Temperature

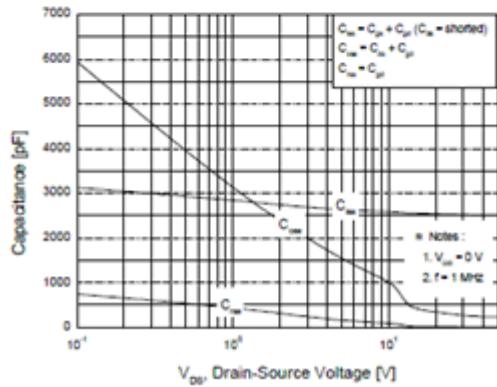


Figure 5. Capacitance Characteristics

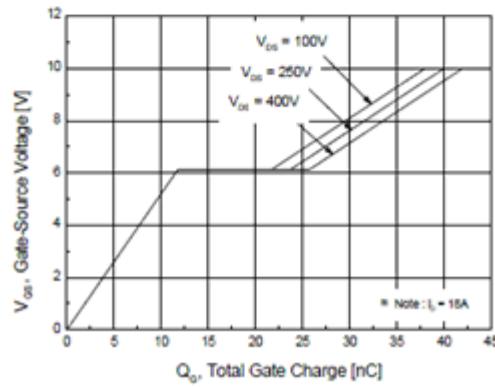


Figure 6. Gate Charge Characteristics

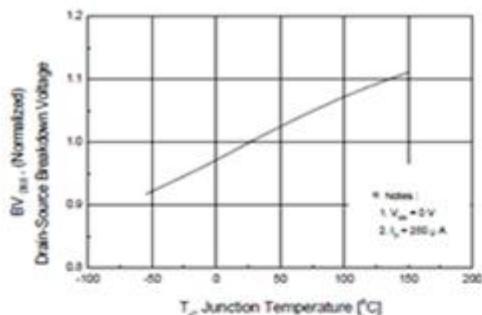


Figure 7. Breakdown Voltage Variation  
vs Temperature

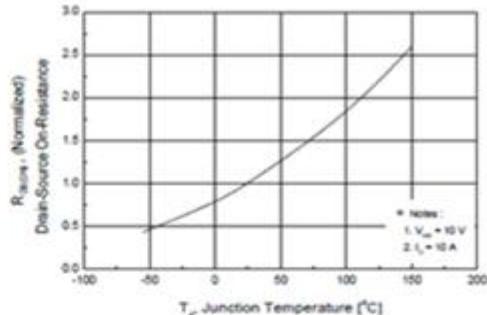


Figure 8. On-Resistance Variation  
vs Temperature

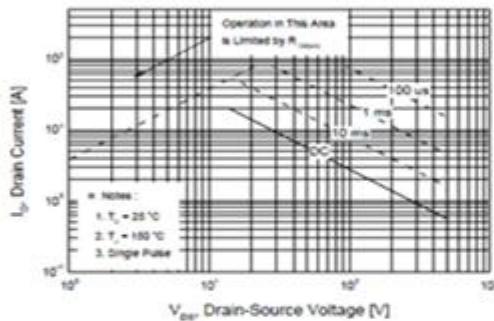


Figure 9. Maximum Safe Operating Area

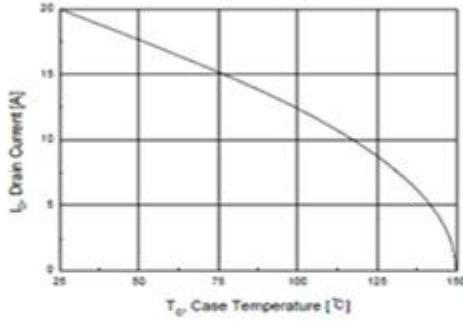


Figure 10. Maximum Drain Current  
vs Case Temperature

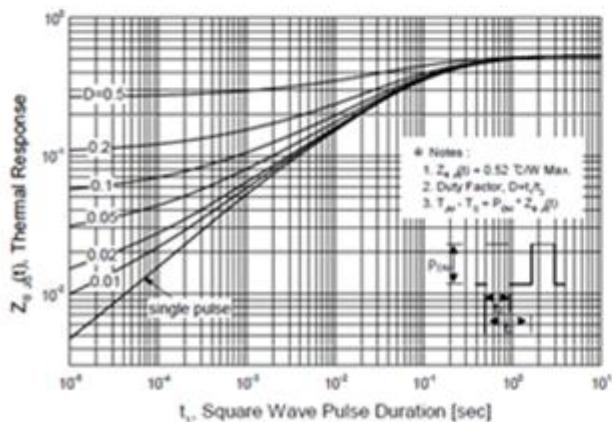


Figure 11. Transient Thermal Response Curve  
for To-247

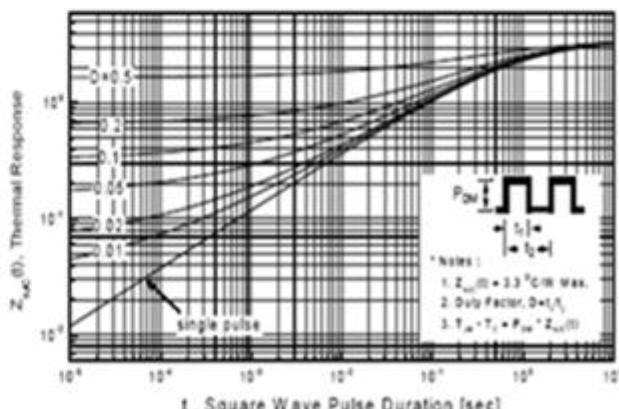


Figure 11-1. Transient Thermal Response Curve  
for To-220F